## Notice of References Cited Application/Control No. 10/691,645 Examiner THUAN T. NGUYEN Applicant(s)/Patent Under Reexamination AHN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,321,073 B1	11-2001	Luz et al.	455/239.1
*	В	US-2003/0068991 A1	04-2003	Lee, Chung Hee	455/126
*	С	US-5,812,025	09-1998	Shimazaki, Yoshihito	330/129
*	D	US-6,625,433 B1	09-2003	Poirier et al.	455/232.1
*	Ε	US-6,640,111 B1	10-2003	Shapira, Joseph	455/562.1
	F	US-			
	G	US-			
	Ι	US-			
	ı	US-			
	٦	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	>	
	8	
	X	

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